

FDN327N

N-Channel 1.8 Vgs Specified PowerTrench® MOSFET

General Description

This 20V N-Channel MOSFET uses Fairchild's high voltage PowerTrench process. It has been optimized for power management applications.

Applications

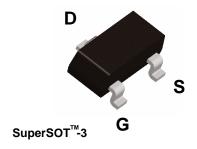
- Load switch
- Battery protection
- Power management

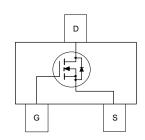
Features

• 2 A, 20 V. $R_{DS(ON)} = 70 \ m\Omega$ @ $V_{GS} = 4.5 \ V$

 $R_{DS(ON)} = 80 \text{ m}\Omega @ V_{GS} = 2.5 \text{ V}$ $R_{DS(ON)} = 120 \text{ m}\Omega @ V_{GS} = 1.8 \text{ V}$

- Low gate charge (4.5 nC typical)
- · Fast switching speed
- High performance trench technology for extremely low R_{DS(ON)}





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		20	V
V _{GSS}	Gate-Source Voltage		± 8	V
I _D	Drain Current - Continuous	(Note 1a)	2	А
	– Pulsed		8	
P _D	Power Dissipation for Single Operation	(Note 1a)	0.5	W
		(Note 1b)	0.46	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	250	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	75	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
327	FDN327N	7"	8mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		·I	I	l	I
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	20			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$		12		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 16 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 8 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I_{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -8 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.4	0.7	1.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		-3		mV/°C
$R_{DS(on)}$	Static Drain–Source On–Resistance	$\label{eq:VGS} \begin{array}{lll} V_{GS} = 4.5 \ V, & I_D = 2.0 \ A \\ V_{GS} = 2.5 \ V, & I_D = 1.9 \ A \\ V_{GS} = 1.8 \ V, & I_D = 1.6 \ A \\ V_{GS} = 4.5 V, I_D = 2 \ A, \ T_J = 125 ^{\circ} C \end{array}$		40 49 65 55	70 80 120 103	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 4.5V$, $V_{DS} = 5 V$	8			Α
g _{FS}	Forward Transconductance	$V_{DS} = 5V$, $I_D = 2 A$		11		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	V _{DS} = 10 V, V _{GS} = 0 V		423		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		87		pF
C _{rss}	Reverse Transfer Capacitance			48		pF
Switchin	g Characteristics (Note 2)	·	•	•		•
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 10 \text{ V}, \qquad I_{D} = 1 \text{ A},$		6	12	ns
t _r	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		6.5	13	ns
t _{d(off)}	Turn-Off Delay Time	7		14	29	ns
t _f	Turn-Off Fall Time	7		2	4	ns
Qg	Total Gate Charge	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 2 \text{ A},$		4.5	6.3	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 4.5 V		0.89		nC
Q_{gd}	Gate-Drain Charge	7		0.95		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings	•	•	•	•
Is	Maximum Continuous Drain–Source				0.42	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 0.42 A (Note 2)		0.6	1.2	V

Notes:

1. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 250°C/W when mounted on a 0.02 in² pad of 2 oz. copper.



b) 270°C/W when mounted on a minimum pad.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%

Typical Characteristics

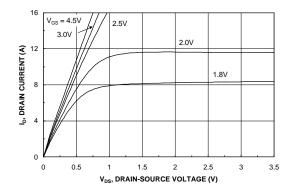


Figure 1. On-Region Characteristics.

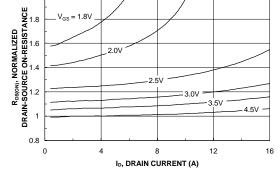


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

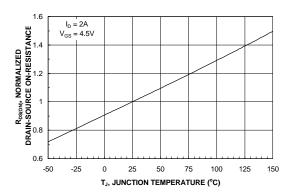


Figure 3. On-Resistance Variation with Temperature.

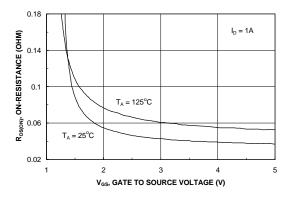


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

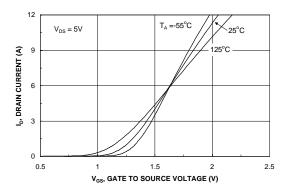


Figure 5. Transfer Characteristics.

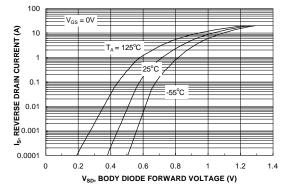
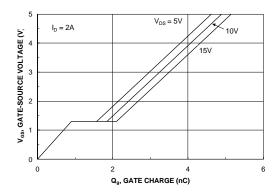


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



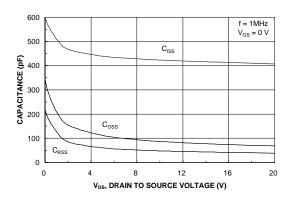


Figure 7. Gate Charge Characteristics.

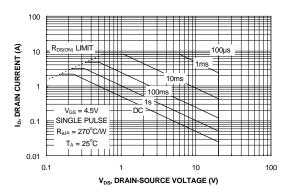


Figure 8. Capacitance Characteristics.

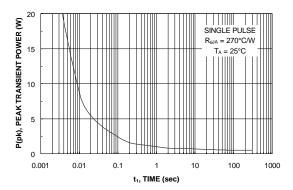


Figure 9. Maximum Safe Operating Area.



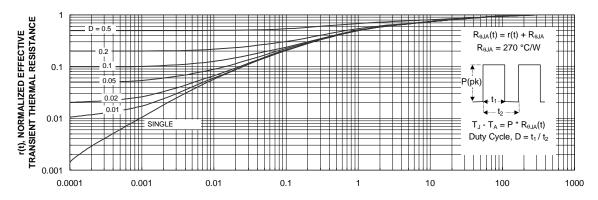


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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